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**FINAL PRODUCT/PROCESS CHANGE NOTIFICATION #16200**

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**Issue Date:** 13-Jan-2015

**TITLE:** Phase 2 Copper Wire for VHVIC Products in SOIC and TSSOP packages in Carmona, Philippines

**PROPOSED FIRST SHIP DATE:** 20-Apr-2015

**AFFECTED CHANGE CATEGORY(S):** Assembly Process

**FOR ANY QUESTIONS CONCERNING THIS NOTIFICATION:**

Contact your local ON Semiconductor Sales Office or <[Scott.Brow@onsemi.com](mailto:Scott.Brow@onsemi.com)>

**SAMPLES:** Contact your local ON Semiconductor Sales Office

**ADDITIONAL RELIABILITY DATA:** Available

Contact your local ON Semiconductor Sales Office or <[Ken.Fergus@onsemi.com](mailto:Ken.Fergus@onsemi.com)>

**NOTIFICATION TYPE:**

Final Product/Process Change Notification (FPCN)

Final change notification sent to customers. FPCNs are issued at least 90 days prior to implementation of the change.

ON Semiconductor will consider this change approved unless specific conditions of acceptance are provided in writing within 30 days of receipt of this notice. To do so, contact <[quality@onsemi.com](mailto:quality@onsemi.com)>.

**DESCRIPTION AND PURPOSE:**

A General Announcement (GA#16200) was published on 1-29-09 regarding the ongoing Copper Wirebond conversion program at ON Semiconductor. This is a FPCN to notify customers of its plan to qualify Copper Wire (in place of Gold Wire) on SOIC and TSSOP packages assembled at the Carmona, Philippine assembly location for the VHVIC products listed in this announcement.

Reliability Qualification and full electrical characterization over temperature has now been completed on the designated package qualification vehicles.



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**RELIABILITY DATA SUMMARY:**

**Reliability Test Results:**

Device NCP1236AD65R2G:

| #  | Test      | Name   | Test Conditions                        | End Point Req's                         | Test Results            | (rej/ ss)    | (rej/ ss)    | (rej/ ss)    | (rej/ ss)            |
|----|-----------|--|--|---|-------------------------|--------------|--------------|--------------|----------------------|
|    |           |  |  |   | Read Point              | Lot A        | Lot B        | Lot C        | Lot 2 AU control lot |
| 1  | Prep      | Sample preparation and initial part testing  | Various                                | ---                                     | Initial Electrical      | Done         | Done         | Done         | Done                 |
| 2  | HTOL      | High Temp Op Life  | TA = 125°C biased                      | c = 0, Room, Hot                        | 504 hours<br>1008 hours | 0/77<br>0/77 | 0/77<br>0/77 | 0/77<br>0/77 | 0/77<br>0/77         |
| 3  | PC        | Preconditioning Test (Test@Rm) SMD only; Moisture preconditioning for HAST, UHAST, TC; Peak reflow Temp = 260C | MSL 1 260                              | Test at R                               |                         | Done         | Done         | Done         | Done                 |
| 4  | PC -HAST  | Preconditioned Highly accelerated stress test  | TA= +130°C, RH = 85%, PSIG= 18.8, bias | c = 0, Room, Hot                        | 96 hours<br>192 hours   | 0/77<br>0/77 | 0/77<br>0/77 | 0/77<br>0/77 | 0/77<br>0/77         |
| 5  | PC -UHAST | Preconditioned Highly accelerated stress test  | TA= +130°C, RH = 85%, PSIG= 18.8       | c = 0, Room, Hot                        | 96 hours<br>192 hours   | 0/77<br>0/77 | 0/77<br>0/77 | 0/77<br>0/77 | 0/77<br>0/77         |
| 6  | PC-TC     | Preconditioned Temperature Cycle   | -65/+150 C                             | c = 0, Room, Hot                        | 500 cye<br>1000cye      | 0/77<br>0/77 | 0/77<br>0/77 | 0/77<br>0/77 | 0/77<br>0/77         |
| 6a | PC-TC DPA | Precond TC DPA AEC decap visual  | -65/+150 C                             | C = 0                                   | 500 cye                 | 0/5          | 0/5          | 0/5          | 0/5                  |
| 6b | WBP       | Wire bond pull test: (Ppk >1.67 and Cpk >1.33)   | Condition C at post 500 cycles         | 30 bonds coming from 5 units Cpk > 1.33 | Post 500cycles TC       | 0/30         | 0/30         | 0/30         | 0/30                 |
| 7  | HTSL      | High Temperature Storage Life  | 150C at 1008hrs                        | c = 0, Room, Hot                        | 504 hours<br>1008 hours | 0/77<br>0/77 | 0/77<br>0/77 | 0/77<br>0/77 | 0/77<br>0/77         |
| 8  | RSH       | Resistance to solder heat  | JESD22 – B106 260°C Immersion          | c = 0, Room, Hot                        | Pass                    | 0/30         | 0/30         | 0/30         | 0/30                 |

Device NCP1654BD65R2G:

| #  | Test      | Name   | Test Conditions                        | End Point Req's                         | Test Results            | (rej/ ss)    | (rej/ ss)    | (rej/ ss)    | (rej/ ss)            |
|----|-----------|--|--|---|-------------------------|--------------|--------------|--------------|----------------------|
|    |           |  |  |   | Read Point              | Lot A        | Lot B        | Lot C        | Lot 2 AU control lot |
| 1  | Prep      | Sample preparation and initial part testing  | Various                                | ---                                     | Initial Electrical      | Done         | Done         | Done         | Done                 |
| 2  | HTOL      | High Temp Op Life  | TA = 125°C biased                      | c = 0, Room, Hot                        | 504 hours<br>1008 hours | 0/77<br>0/77 | 0/77<br>0/77 | 0/77<br>0/77 | 0/77<br>0/77         |
| 3  | PC        | Preconditioning Test (Test@Rm) SMD only; Moisture preconditioning for HAST, UHAST, TC; Peak reflow Temp = 260C | MSL 1 260                              | Test at R                               |                         | Done         | Done         | Done         | Done                 |
| 4  | PC -HAST  | Preconditioned Highly accelerated stress test  | TA= +130°C, RH = 85%, PSIG= 18.8, bias | c = 0, Room, Hot                        | 96 hours<br>192 hours   | 0/77<br>0/77 | 0/77<br>0/77 | 0/77<br>0/77 | 0/77<br>0/77         |
| 5  | PC -UHAST | Preconditioned Highly accelerated stress test  | TA= +130°C, RH = 85%, PSIG= 18.8       | c = 0, Room, Hot                        | 96 hours<br>192 hours   | 0/77<br>0/77 | 0/77<br>0/77 | 0/77<br>0/77 | 0/77<br>0/77         |
| 6  | PC-TC     | Preconditioned Temperature Cycle   | -65/+150 C                             | c = 0, Room, Hot                        | 500 cye<br>1000cye      | 0/77<br>0/77 | 0/77<br>0/77 | 0/77<br>0/77 | 0/77<br>0/77         |
| 6a | PC-TC DPA | Precond TC DPA AEC decap visual  | -65/+150 C                             | C = 0                                   | 500 cye                 | 0/5          | 0/5          | 0/5          | 0/5                  |
| 6b | WBP       | Wire bond pull test: (Ppk >1.67 and Cpk >1.33)   | Condition C at post 500 cycles         | 30 bonds coming from 5 units Cpk > 1.33 | Post 500cycles TC       | 0/30         | 0/30         | 0/30         | 0/30                 |
| 7  | HTSL      | High Temperature Storage Life  | 150C at 1008hrs                        | c = 0, Room, Hot                        | 504 hours<br>1008 hours | 0/77<br>0/77 | 0/77<br>0/77 | 0/77<br>0/77 | 0/77<br>0/77         |
| 8  | RSH       | Resistance to solder heat  | JESD22 – B106 260°C Immersion          | Test at R                               | Pass                    | 0/30         | 0/30         | 0/30         | 0/30                 |



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**ELECTRICAL CHARACTERISTIC SUMMARY:**

There is no electrical characterization difference in products assembled with copper wire. Electrical data is available upon request.

**CHANGED PART IDENTIFICATION:**

Products affected on this FPCN will have part number date codes greater than WW16 2015.

**List of affected General Parts:**

|                  |                  |                  |
|------------------|------------------|------------------|
| NCL30000DR2G     | NCP1246BD065R2G  | NCP1397BDR2G     |
| NCL30001DR2G     | NCP1246BD100R2G  | NCP1398BDR2G     |
| NCL30002DR2G     | NCP1246BLD065R2G | NCP1398CDR2G     |
| NCL30051DR2G     | NCP1246BLD100R2G | NCP1562ADR2G     |
| NCP1218AD65R2G   | NCP1247AD065R2G  | NCP1562BDR2G     |
| NCP1219AD100R2G  | NCP1247AD100R2G  | NCP1607BDR2G     |
| NCP1219AD65R2G   | NCP1247BD065R2G  | NCP1608BDR2G     |
| NCP1219BD100R2G  | NCP1247BD100R2G  | NCP1631DR2G      |
| NCP1219BD65R2G   | NCP1247CD065R2G  | NCP1652ADR2G     |
| NCP1234AD100R2G  | NCP1247CD100R2G  | NCP1652DR2G      |
| NCP1234AD65R2G   | NCP1247DD065R2G  | NCP1652DWR2G     |
| NCP1234BD100R2G  | NCP1247DD100R2G  | NCP1654BD133R2G  |
| NCP1234BD65R2G   | NCP1252ADR2G     | NCP1654BD200R2G  |
| NCP1236AD100R2G  | NCP1252BDR2G     | NCP1654BD65R2G   |
| NCP1236AD65R2G   | NCP1252CDR2G     | NCP1910A100DWR2G |
| NCP1236BD100R2G  | NCP1271D100R2G   | NCP1910A65DWR2G  |
| NCP1236BD65R2G   | NCP1271D65R2G    | NCP1910B100DWR2G |
| NCP1236DD65R2G   | NCP1288BD65R2G   | NCP1910B65DWR2G  |
| NCP1237AD65R2G   | NCP1336ADR2G     | NCP1927DR2G      |
| NCP1237BD65R2G   | NCP1336BDR2G     | NCP4304ADR2G     |
| NCP1238AD65R2G   | NCP1379DR2G      | NCP4304BDR2G     |
| NCP1238BD65R2G   | NCP1380ADR2G     | NCP4810DR2G      |
| NCP1240AD100R2G  | NCP1380BDR2G     | NCP5104DR2G      |
| NCP1244AD065R2G  | NCP1380CDR2G     | NCP5106ADR2G     |
| NCP1244AD100R2G  | NCP1380DDR2G     | NCP5106BDR2G     |
| NCP1244BD065R2G  | NCP1392BDR2G     | NCP5109ADR2G     |
| NCP1244BD100R2G  | NCP1392DDR2G     | NCP5109BDR2G     |
| NCP1246AD065R2G  | NCP1393BDR2G     | NCP5111DR2G      |
| NCP1246AD100R2G  | NCP1396ADR2G     | NCP5304DR2G      |
| NCP1246ALD065R2G | NCP1396BDR2G     | SCY99102BDR2G    |
| NCP1246ALD100R2G | NCP1397ADR2G     | SCY991608BDR2G   |